“On wafer” SVX3D yields

4-in Honeywell batches (118 wafers probed):

Dice probed:	6114 (100 %)
Good dice:	3091 (50.6 %)
Good + Fair dice:	3799 (62.1 %)

6-in lot 8 (18 wafers probed):

	Including / Excluding scratched dice
Dice probed:	2520 / 2026 (100 / 100 %)
Good dice:	1067 (42.3 / 52.7 %)
Good + Fair dice:	1330 (52.8 / 65.6 %)

6-in lots 9 and 12 (33 wafers probed):

Dice probed:	4422 (100 %)
Good dice:	1758 (39.7 %)
Good + Fair dice:	2357 (53.3 %)

The wafer quality maps are on the WWW at

http://cdfsg6.lbl.gov/~igv/svxmaps.html